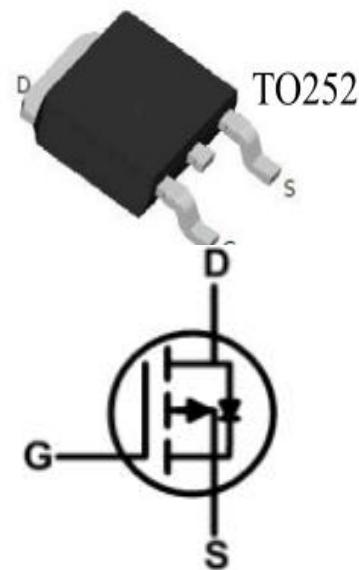


## 30V P-Channel Fast Switching MOSFET

### ■ Features

- $V_{DSS} = -30V$   $I_D = -70A$
- $R_{DS(ON)} = 7.2m\Omega$ (max.)@ $V_{GS} = -10V$
- $R_{DS(ON)} = 12m\Omega$ (max.)@ $V_{GS} = -4.5V$
- Excellent CdV/dt effect decline
- Super Low Gate Charge
- 100% EAS Guaranteed
- Green Device Available
- Advanced high cell density Trench technology

### ■ PIN DESCRIPTION



### ■ Applications

- The SI3031D is the high cell density trenched P-ch MOSFETS, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.
- The SI3031D meet the ROHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Part Number	Package	Marking	ROHS Status	Packing
SI3031D	TO-252	D3031	Halogen-Free	Tape&Reel

### ■ Absolute Maximum Ratings ( $T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Unit	
$V_{DS}$	Drain-Source Voltage	-30	V	
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V	
$I_D$	Continuous Drain Current, $V_{GS} = -10V$	$T_c = 25^\circ C$	-70	A
		$T_c = 100^\circ C$	-50	A
$I_{DM}$	Pulsed Drain Current	-200	A	
$I_{AS}$	Avalanche Current	-40	A	
$E_{AS}$	Single Pulse Avalanche Energy	80	mJ	
$T_J, T_{STG}$	Operating Junction and Storage Temperature Range	-55 to 150	°C	
$P_D$	Total Power Dissipation	$T_c = 25^\circ C$	90	W

### ■ THERMAL RESISTANCE RATINGS

Symbol	Parameter	Typical	Max	Unit
$R_{\theta JA}$	Maximum Junction-to-Ambient (Steady State)	-	50	°C/W
	Maximum Junction-to-Ambient ( $t \leq 10S$ )	-	20	
$R_{\theta JC}$	Maximum Junction-to-Case	-	1.6	

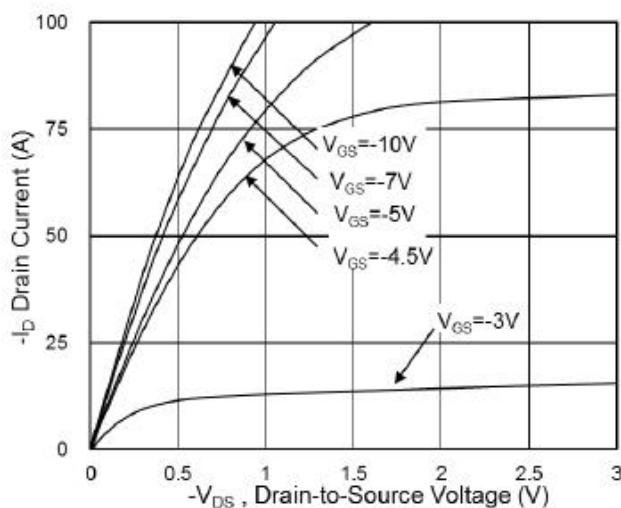
## Electrical Characteristics (TJ=25°C unless otherwise Ratings )

Symbol	Parameter	Test Conditions	Min.	TYP.	Max.	Unit
<b>Static Characteristics</b>						
B <sub>VDSS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =-250uA	-30	-	-	V
V <sub>GS(th)</sub>	Gate threshold voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =-250uA	-1.2	-	-2.5	V
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V T <sub>j</sub> =25°C	-	-	-1	uA
		V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V, T <sub>j</sub> =55°C	-	-	-5	uA
I <sub>GSS</sub>	Gate-source leakage current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
R <sub>DS(on)</sub>	Drain-source on-state resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A	-	-	7.2	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> =-15A	-	-	12	mΩ
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V , f=1MHz	-	1.2	-	Ω
<b>Dynamic Characteristic</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V I <sub>D</sub> =-18A	-	60	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	9	-	nC
Q <sub>gd</sub>	Gate-Drain Charge		-	15	-	nC
T <sub>d(on)</sub>	Turn-on delay time	I <sub>D</sub> =-20A, V <sub>GS</sub> =-10V V <sub>DD</sub> =-15V, R <sub>G</sub> =3.3Ω	-	17	-	nS
T <sub>r</sub>	Rise time		-	40	-	nS
T <sub>d(off)</sub>	Turn-off delay time		-	55	-	nS
T <sub>f</sub>	Fall time		-	13	-	nS
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V f=1.0MHz	-	3450	-	pF
C <sub>oss</sub>	Output Capacitance		-	255	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	140	-	pF
<b>Source-Drain Diode</b>						
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A	-	-	-1.2	V
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V Force Current	-	-	-70	A
T <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> =-20A, T <sub>j</sub> =25°C dI/dt=100A/μs	-	22	-	nS
Q <sub>rr</sub>	Reverse Recovery Charge		-	72	-	nC

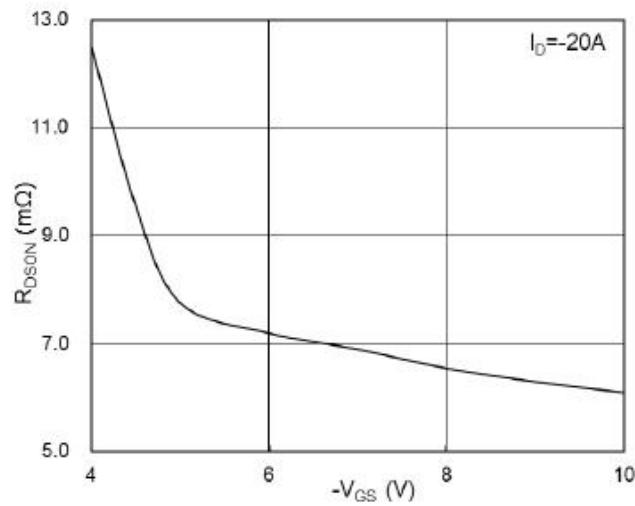
**Notes:**

1. The data tested by surface mounted on a 1 inch <sup>2</sup> FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width  $\leq$ 300us , duty cycle  $\leq$ 2%
- 3.The E<sub>AS</sub> data shows Max.rating .The test condition is V<sub>DD</sub>=-50V, V<sub>GS</sub>=-10V,L=0.1mH,I<sub>AS</sub>=-40A
- 4.The power dissipation is limited by 150 °C junction temperature
- 5.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

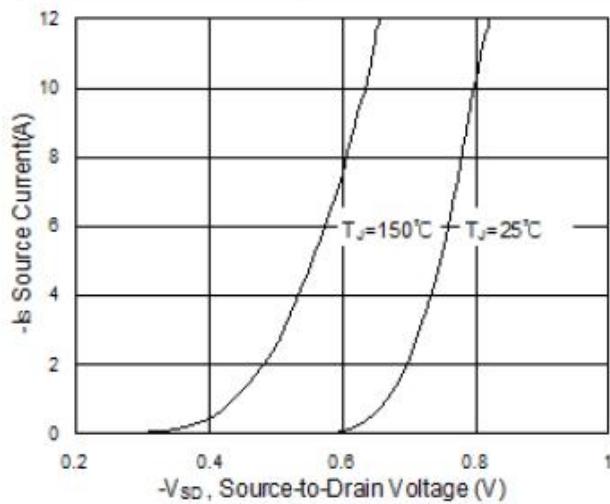
## Typical Performance Characteristics



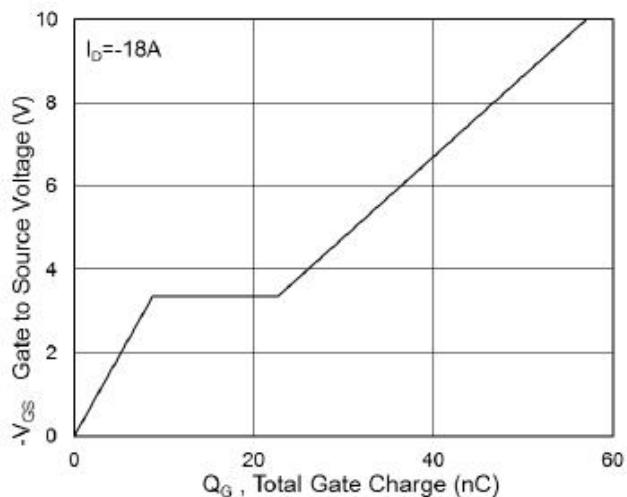
**Fig.1 Typical Output Characteristics**



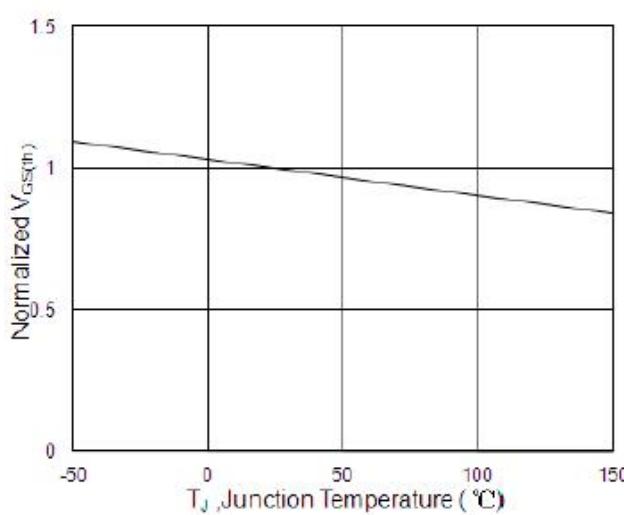
**Fig.2 On-Resistance vs. Gate-Source Voltage**



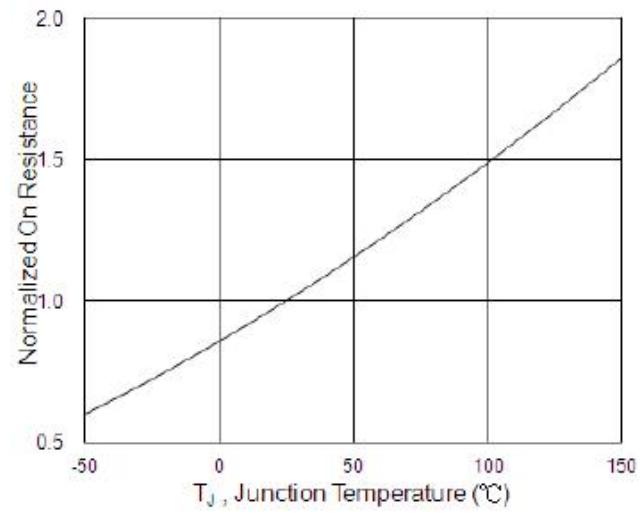
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

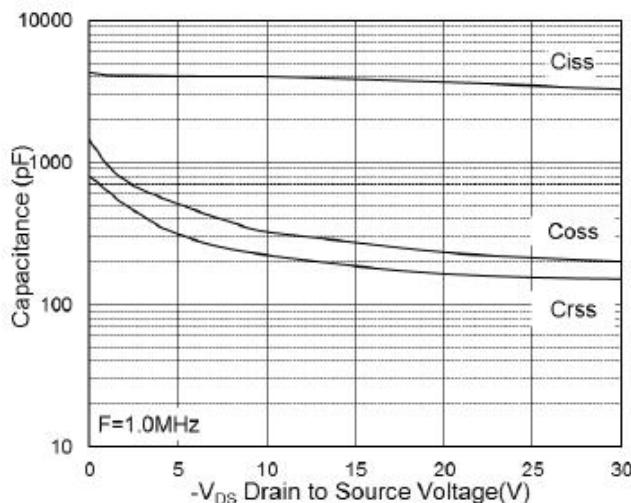


**Fig.5 Normalized  $-V_{GS(th)}$  vs.  $T_J$**

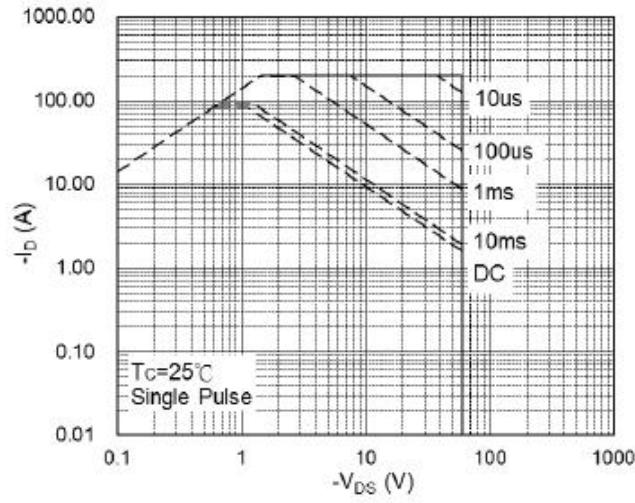


**Fig.6 Normalized  $R_{DSON}$  vs.  $T_J$**

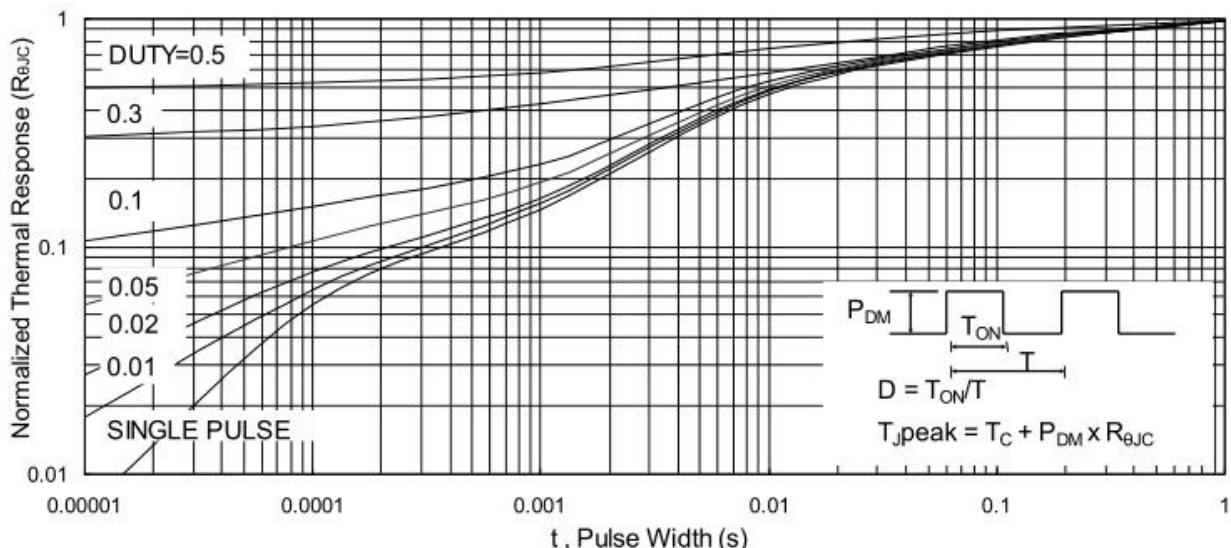
### Typical Performance Characteristics (Cont.)



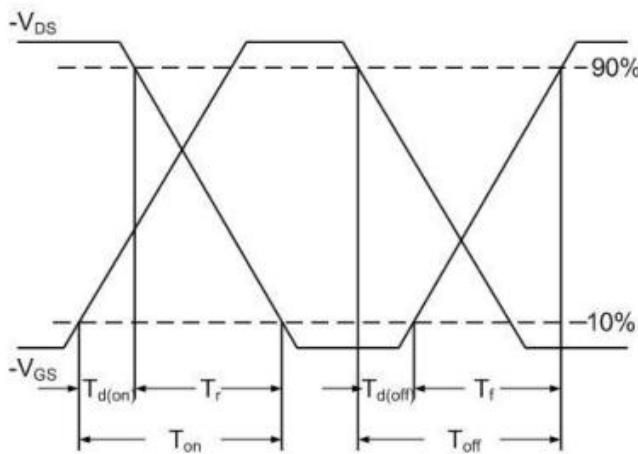
**Fig.7 Capacitance**



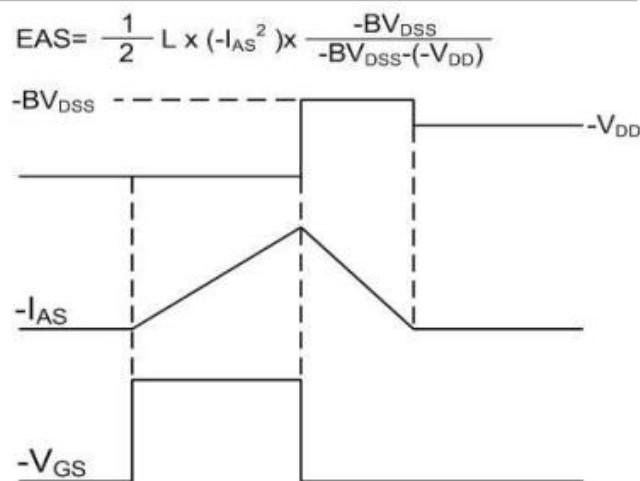
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**

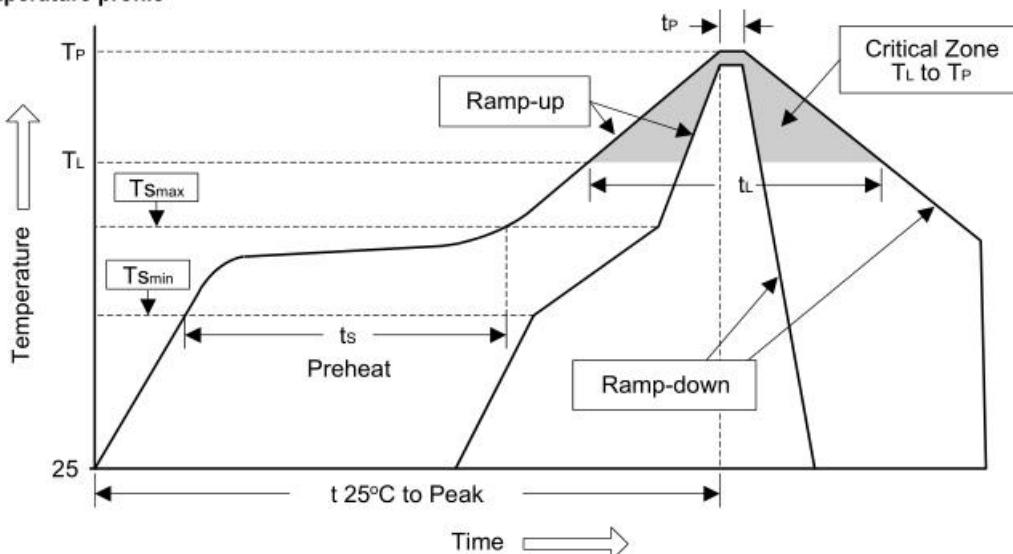


**Fig.11 Unclamped Inductive Waveform**

## Soldering Methods for Products

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate(TL to TP)	<3°C/sec	<3°C/sec
Preheat -Temperature Min(Ts min) -Temperature Max(Ts max) -Time(min to max)(ts)	- 100°C 150°C 60 to 120 sec	- 150°C 200°C 60 to 180 sec
Ts max to TL - ramp-up rate	<3°C/sec	<3°C/sec
Time maintained above: -Temperature(TL) -Time(TL)	183°C 60 to 150 sec	217°C 60 to 150 sec
Peak Temperature(TP)	240°C+0/-5°C	250°C+0/-5°C
Time within 5°C of actual Peak Temperature	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25 °C to Peak Temperature	<6 minutes	<8 minutes

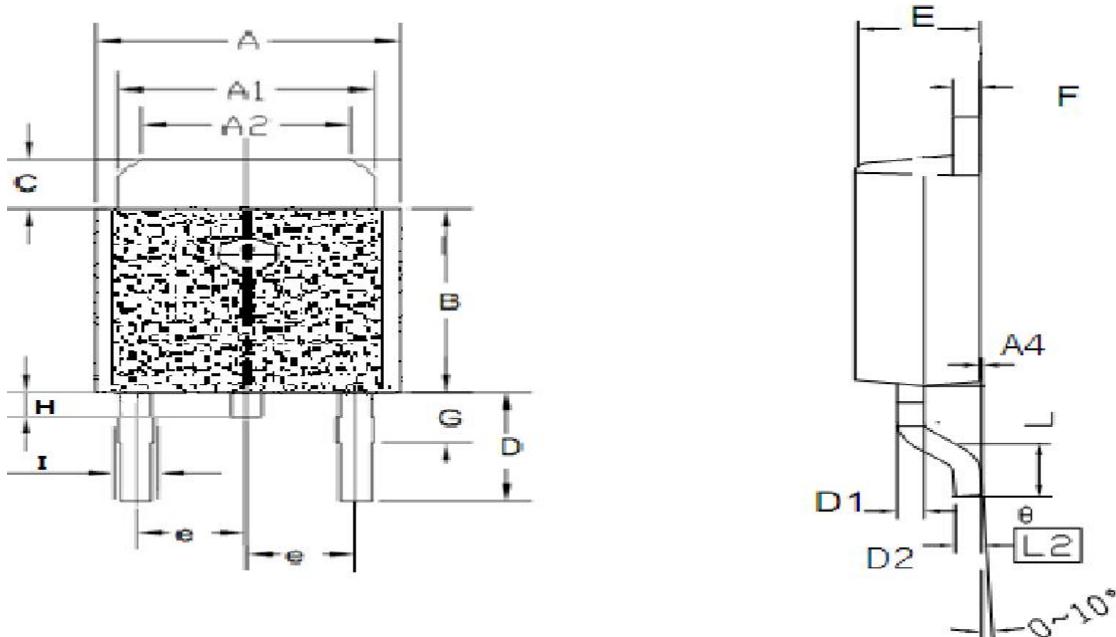
Figure 1: Temperature profile



- Note :**
- 1.Storage environment: Temperature=10°C to 35@Humidity=45%±15%
  - 2.Reflow soldering of surface-mount devices
  - 3.Flow(wave) soldering(solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices	245°C±5°C	5sec±1sec
Pb-free devices	250°C+0/-5°C	5sec±1sec

## Package Outline



unit: mm					
Symbol	Min	Max	Symbol	Min	Max
<b>A</b>	6.40	6.60	<b>D</b>	2.90	3.10
<b>A1</b>	5.20	5.40	<b>D1</b>	0.45	0.55
<b>A2</b>	4.40	4.60	<b>D2</b>	0.45	0.55
<b>A3</b>	4.40	4.60	<b>e</b>	2.3BSC	
<b>A4</b>	0.00	0.15	<b>E</b>	2.20	2.40
<b>A5</b>	4.65	4.95	<b>F</b>	0.49	0.59
<b>B</b>	6.00	6.20	<b>G</b>	1.7BSC	
<b>B1</b>	1.57	1.77	<b>L</b>	1.40	1.60
<b>C</b>	0.90	0.96	<b>θ(度)</b>	0.00	10.00
<b>I</b>	0.80	0.85	<b>H</b>	0.49	0.52

## ■ Important Notice

Si-Trend reserves the right to change all product、product specifications and data without prior notice ; Our customer Please confirm to place an order confirmation before make the integrity of information complete and up-to-date 。

Any semiconductor under specific conditions are possible to certain failure or malfunction rate ; Customers are responsible in the use of Si-Trend products to system design and manufacturing in compliance with safety standards and adopting safety measures , To avoid the potential risk of failure may cause the personal safety and property loss 。

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## ■ Modify record

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